1. Record Nr. UNINA9910458831203321

Titolo	Microscopy of oxidation 2 [[electronic resource]] : proceedings of the Second International Conference on the Microscopy of Oxidation, held at Selwyn College, the University of Cambridge, 29-31 March 1993 / / edited by S.B. Newcomb and M.J. Bennett
Pubbl/distr/stampa	London, : Institute of Materials, 1993
ISBN	1-62198-514-8 1-907747-24-9
Descrizione fisica	1 online resource (608 p.)
Collana	Book ; ; 552
Altri autori (Persone)	NewcombS. B BennettM. J
Disciplina	541.393
Soggetti	Oxidation Chemical microscopy Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	"Sponsored and organised by the Materials Science Committee of The Institute of Materials with the co-sponsorship of The Institute of Physics and The Royal Microscopical Society."
Nota di bibliografia	Includes bibliographical references and indexes.
Nota di contenuto	Contents; Preface; Keynote Papers: Status and Potential of Newer Microscopical Techniques in Oxidation Studies; High-Resolution Transmission Electron Microscopy of Metal/ Metal Oxide Interfaces; Application of Dynamic Secondary Ion Mass Spectrometry to the Study of Oxidation; The Use of a Hot-Stage Microscope in High-Temperature Corrosion Studies; Developments in Raman Microscopy and Applications to Oxidation Studies; Acoustic Microscopy of Oxidation; Oxidation of Mild and Low Alloy Steels Study of the Corrosion of Steel in Concrete by Backscattered Electron Imaging in the Scanning Electron MicroscopeThe Study of Atmospheric Corrosion in Steel by Backscattered Electron Imaging; Oxidation of a Precipitation-Strengthened Die Steel; Mixed Oxidant Corrosion in Non-equilibrium CO-CO2 -H2-H2S Gas Mixtures at 400 and 550°; Oxidation of Nickel, Chromium and Their Alloys; Scanning Tunnelling Microscopy Study of the Atomic Structure of Thin Anodic Oxide Films Grown on Nickel Crystal Surfaces; The Incorporation of Internal Oxide

Precipitates into Growing Oxide and Sulphide External Scales
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Oxidation of Incoloy MA956 After Long-term Exposure to Nitrogen-containing Atmospheres at 1200°C

Sommario/riassunto

An understanding of oxidation is essential for the study and development of advanced materials, particularly those which must withstand high temperatures. The 56 papers in this volume examine the behaviour of metals, alloys and ceramics when exposed to different environments and discuss the latest analytical microscopical techniques currently used in materials science.